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Computation of waveform Parameter uncertainties

Táto norma obsahuje anglickú verziu európskej normy.  
This standard includes the English version of the European Standard.

Táto norma bola oznámená vo Vestníku ÚNMS SR č. 02/18

Obsahuje: EN 62754:2017, IEC 62754:2017

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ICS 17.220.20

English Version

**Computation of waveform Parameter uncertainties  
(IEC 62754:2017)**Calcul des incertitudes des paramètres des formes d'onde  
(IEC 62754:2017)Berechnung der Messunsicherheiten von  
Schwingungsabbildparametern  
(IEC 62754:2017)

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Comité Européen de Normalisation Electrotechnique  
Europäisches Komitee für Elektrotechnische Normung

**CEN-CENELEC Management Centre: Avenue Marnix 17, B-1000 Brussels**

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## European foreword

The text of document 85/585/FDIS, future edition 1 of IEC 62754, prepared by IEC/TC 85 "Measuring equipment for electrical and electromagnetic quantities" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 62754:2017.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2018-03-28
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In the official version, for Bibliography, the following notes have to be added for the standard indicated :

IEC 60359:2001

NOTE

Harmonized as EN 60359:2002.

## Annex ZA (normative)

### Normative references to international publications with their corresponding European publications

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 When an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: [www.cenelec.eu](http://www.cenelec.eu).

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60469	2013	Transitions, pulses and related waveforms - Terms, definitions and algorithms	EN 60469	2013



# INTERNATIONAL STANDARD

# NORME INTERNATIONALE



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**Computation of waveform parameter uncertainties**

**Calcul des incertitudes des paramètres des formes d'onde**





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# INTERNATIONAL STANDARD

# NORME INTERNATIONALE



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**Computation of waveform parameter uncertainties**

**Calcul des incertitudes des paramètres des formes d'onde**

INTERNATIONAL  
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**COMPUTATION OF WAVEFORM PARAMETER UNCERTAINTIES**

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FDIS	Report on voting
85/585/FDIS	85/X588/RVD

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## COMPUTATION OF WAVEFORM PARAMETER UNCERTAINTIES

### 1 Scope

This document specifies methods for the computation of the temporal and amplitude parameters and their associated uncertainty for step-like and impulse-like waveforms. This document is applicable to any and all industries that generate, transmit, detect, receive, measure, and/or analyse these types of pulses.

### 2 Normative references

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IEC 60469:2013, *Transitions, pulses and related waveforms – Terms, definitions and algorithms*

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